Notice of References Cited Application/Control No. 10/571,292 Examiner John R. Lee Applicant(s)/Patent Under Reexamination SUYAMA ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,780,913	07-1998	Muramatsu et al.	257/429
	В	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-		·	
	G	US-			
	π	US-	,		
	-	US-			
	J	US-			
	К	US- ,			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0	,				
	Р					
	Q					
	R	•				·
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	V						
	w						
	×						

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.